Notice of References Cited Application/Control No. 10/695,791 Examiner Patrick J. Lee Applicant(s)/Patent Under Reexamination TANAKA ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-2003/0047673 A1	03-2003	Thorburn et al.	250/231.13
	В	US-			
	С	US-			
	Δ.	US-			
	Е	US-			
	F	US-		·	
	G	US-			
	Н	US-			
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	J	US-			
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FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification		
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